

Cairnhill Metrology Pte Ltd (198303929M)

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2D/3D NDT Inspection for Electronics and Advanced Manufacturing

Struggling with hidden defects or slow inspection processes?

Get practical solutions at our exclusive seminar on non-destructive testing for Electronics and Advanced Manufacturing. This complimentary session will share actionable insights on advanced 2D and 3D X-ray CT to future-proof your quality control, enhance product reliability, and improve overall inspection processes.

Date	Wednesday, 20 August 2025		
Time	09:30 AM to 12:30 PM (Registration begins at 09:00 AM)		
Venue	Cairnhill Metrology 5 Jalan Kilang Barat #07-05 Petro Centre, Singapore 159349		
Our speakers	KC Lye	Pakasa Sira	
	Senior Sales Manager Waygate Technologies	Rebecca Sim Technical Sales Specialist VOLUME GRAPHICS	Dr. Jakub Šalplachta CEO CACTUX
Topics	 2D / 3D NDT Inspection Solutions for Electronics and Advanced Manufacturing Insights to the insides: XCT for Electronics & Advanced Manufacturing In-Situ Soldering Process Simulation during Radiography Imaging 		

Why Should You Attend

- If you're facing issues with defects in complex assemblies, solder joints, or internal structures, seeking to elevate your quality control
- Learn practical applications of non-destructive testing, focusing on how 2D and 3D X-ray technologies can solve your most pressing quality inspection issues
- See how the Waygate Nanomex Neo system integrates seamlessly into your workflow, driving efficiency and accuracy in your inspection processes
- Connect with industry specialists and understand how our state-of-the-art NDT solutions can transform your approach to quality assurance

Register <u>here</u> or send us an email at <u>sales@cairnhill.com</u>. Allocation on a <u>first-come</u>, <u>first-served basis</u>.

Lunch & Refreshments are provided

You may also approach our team for a one-to-one private discussion